

M5M27C202K, JK-12I, -15I

2097152-BIT(131072-WORD BY 16-BIT)
CMOS ERASABLE AND ELECTRICALLY REPROGRAMMABLE ROM

DESCRIPTION

The Mitsubishi M5M27C202K, JK-12I, -15I are high-speed 2097152-bit ultraviolet erasable and electrically reprogrammable read only memories. They are suitable for micro-processor programming applications where rapid turn-around is required. The M5M27C202K, JK-12I, -15I are fabricated by N-channel double polysilicon gate for Memory and CMOS technology for peripheral circuits, and are available in a 40-pin DIP or 44-pin CLCC with a transparent lid.

FEATURES

- 131072 word × 16 bit organization
- Access time
 - M5M27C202K-12I, JK-12I 120ns (max.)
 - M5M27C202K-15I, JK-15I 150ns (max.)
- Two line control \overline{OE} , \overline{CE}
- Low power current (I_{cc}): Active 30mA (max.)
 (Stand-by) 0.1mA (max.)
- Single 5v power supply (read operation)
- Programming voltage 12.5V
- 3-State output buffer
- Input and output TTL-compatible in read and program mode
- Standard 40-pin DIP
- Word programming algorithm
- Page programming algorithm
- Wide temperature range: - 40°C ~ + 85°C

APPLICATION

Microcomputer systems and peripheral equipment

FUNCTION

Read

Set the \overline{CE} and \overline{OE} terminals to the read mode (low level). Low level input to \overline{CE} and \overline{OE} and address signals to the address inputs ($A_0 \sim A_{16}$) make the data contents of the designated address location available at the data input/output ($D_0 \sim D_{15}$). When the \overline{CE} or \overline{OE} signal is high, data input/output are in a floating state.

When the \overline{CE} signal is high, the device is in the stand by mode or power-down mode.

Programming

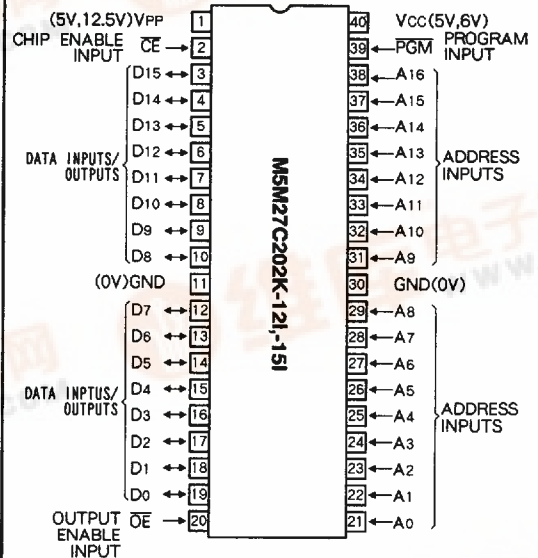
(Word programming algorithm)

The M5M27C202K, JK-12I, -15I enter the word programming mode when 12.5V is supplied to the V_{PP} power supply input, \overline{CE} is at low level and \overline{OE} is at high level. A location is designated by address signals ($A_0 \sim A_{16}$), and the data to be programmed must be applied at 16-bits in parallel to the data inputs ($D_0 \sim D_{15}$). In this state, word programming is completed when \overline{PGM} is at low level.

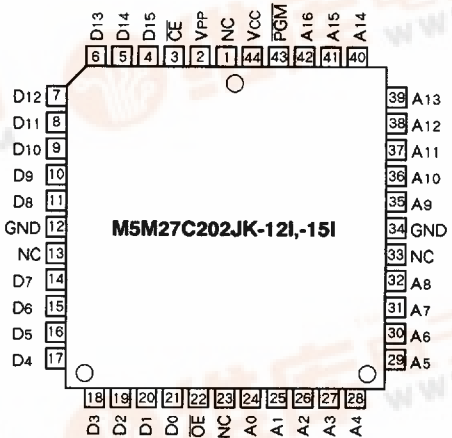
(Page programming algorithm)

Page programming feature of the M5M27C202K, JK-12I, -15I allows 2 words of data to be simultaneously programmed. The destination addresses for a page programming operation must reside on the same page; that is, A_1 through A_{16} must not change. At first, the M5M27C202K, JK-12I, -15I enter

PIN CONFIGURATION (TOP VIEW)



Outline 40K4 (CERDIP: K)



Outline 44K0 (CLCC: JK)

NC: NO CONNECTION

the page data latch mode when $V_{PP} = 12.5V$, $\overline{CE} = "H"$, $\overline{OE} = "L"$ and $\overline{PGM} = "H"$. A first and second locations in same page are designated by address signals ($A_0 \sim A_{16}$), and the data to be programmed must be applied to each location at 16-bits in parallel to the data inputs ($D_0 \sim D_{15}$). In this state, the data (2 words) latch is completed. Then the M5M27C202K, JK-12I, -15I enter the page programming mode when $\overline{OE} = "H"$. In this state page (2 words) programming is completed when $\overline{PGM} = "L"$.



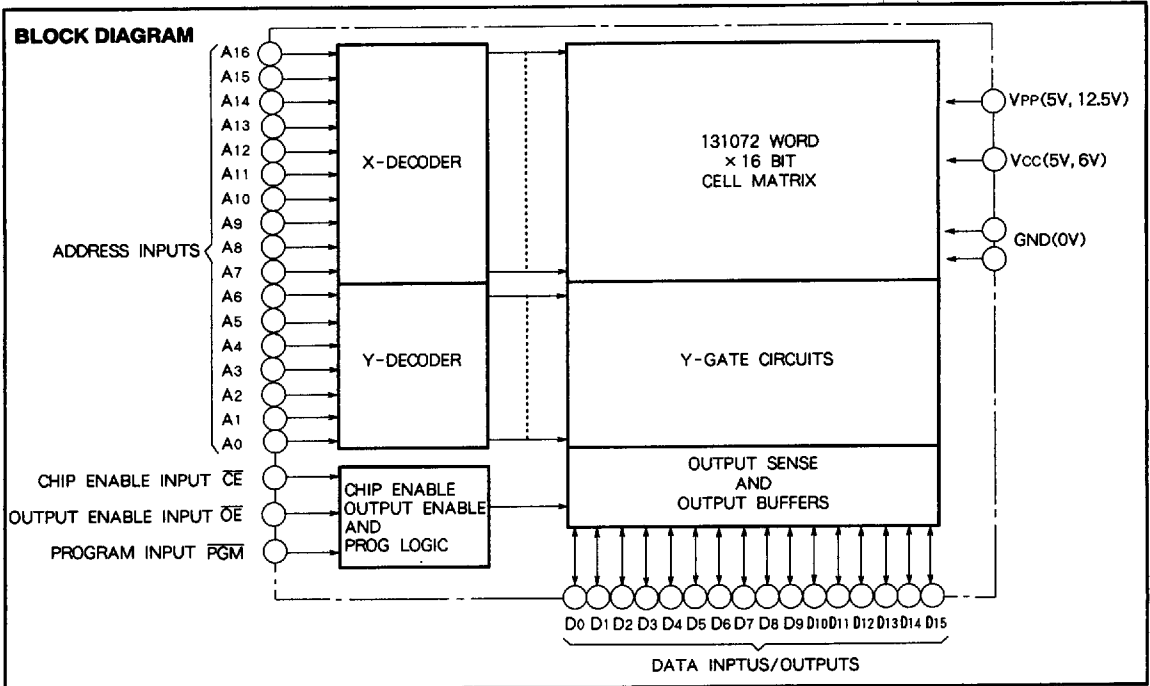
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Erase

Erase is effected by exposure to ultraviolet light with a wavelength of 2537Å at an intensity of approximately 15WS/cm². Sunlight and fluorescent light may contain ultraviolet

light sufficient to erase the programmed information. For any operation in the read mode, the transparent lid should be covered with opaque tape.



MODE SELECTION

Mode \ Pins (K/JK)	CE (2/3)	OE (20/22)	PGM (39/43)	VPP (1/2)	VCC (40/44)	Data I/O (3~10, 12~19/4~11, 14~21)
Read	V _{IL}	V _{IL}	X*	5V	5V	Data out
Output disable	V _{IL}	V _{IH}	X*	5V	5V	Floating
Standby (Power down)	V _{IH}	X*	X*	5V	5V	Floating
Word program	V _{IL}	V _{IH}	V _{IL}	12.5V	6V	Data in
Program verify	V _{IL}	V _{IL}	V _{IH}	12.5V	6V	Data out
Page data latch	V _{IH}	V _{IL}	V _{IH}	12.5V	6V	Data in
Page program	V _{IH}	V _{IH}	V _{IL}	12.5V	6V	Floating
Program inhibit	V _{IL}	V _{IL}	V _{IL}	12.5V	6V	Floating
	V _{IL}	V _{IH}	V _{IH}	12.5V	6V	
	V _{IH}	V _{IL}	V _{IL}	12.5V	6V	
	V _{IH}	V _{IH}	V _{IH}	12.5V	6V	

* : X can be either V_{IL} or V_{IH}.

ABSOLUTE MAXIMUM RATINGS (Note 1)

Symbol	Parameter	Conditions	Ratings	Unit
V _{I1}	All input or output voltage except V _{PP} · A ₉	With respect to Ground	-0.6~7	V
V _{I2}	V _{PP} supply voltage		-0.6~14.0	V
V _{I3}	A ₉ supply voltage		-0.6~13.5	V
T _{opr}	Operating temperature		-50~95	°C
T _{stg}	Storage temperature		-65~125	°C

Note 1 : Stresses above those listed may cause permanent damage to the device. This is a stress rating only and functional operation of the device at those or at any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods affects device reliability.

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READ OPERATION

DC ELECTRICAL CHARACTERISTICS ($T_a = -40 \sim 85^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$, $V_{PP} = V_{CC}$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
I_{LI}	Input leakage current	$V_{IN} = 0 \sim V_{CC}$			10	μA
I_{LO}	Output leakage current	$V_{OUT} = 0 \sim V_{CC}$			10	μA
I_{PP1}	V_{PP} current read/stand-by	$V_{PP} = V_{CC} = 5.5V$		1	100	μA
I_{SB1}	V_{CC} current stand-by	$\overline{CE} = V_{IH}$			1	mA
I_{SB2}		$\overline{CE} = V_{CC}$		1	100	μA
I_{CC1}	V_{CC} current Active	$\overline{CE} = \overline{OE} = V_{IL}$, DC, $I_{OUT} = 0\text{mA}$			30	mA
I_{CC2}		$\overline{CE} = V_{IL}$, $f = 8.3\text{MHz}$, $I_{OUT} = 0\text{mA}$			30	mA
V_{IL}	Input low voltage		-0.1		0.8	V
V_{IH}	Input high voltage		2.4		$V_{CC} + 1$	V
V_{OL}	Output low voltage	$I_{OL} = 2.1\text{mA}$			0.45	V
V_{OH}	Output high voltage	$I_{OH} = -400 \mu\text{A}$	2.4			V

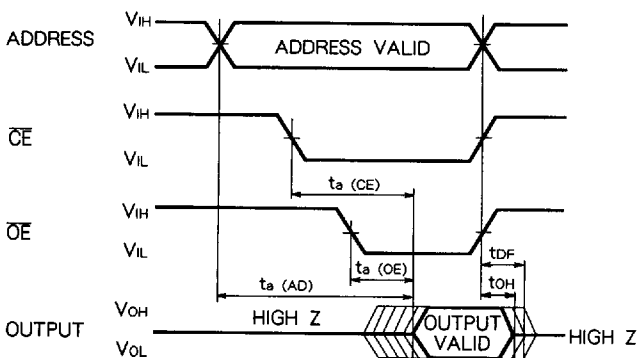
Note 2: Typical values are at $T_a = 25^\circ\text{C}$ and nominal supply voltage.

AC ELECTRICAL CHARACTERISTICS ($T_a = -40 \sim 85^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$, $V_{PP} = V_{CC}$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits				Unit
			M5M27C202K-12I		M5M27C202K-15I		
			Min	Max	Min	Max	
$t_{a(AD)}$	Address to output delay	$\overline{CE} = \overline{OE} = V_{IL}$		120		150	ns
$t_{a(CE)}$	\overline{CE} to output delay	$\overline{OE} = V_{IL}$		120		150	ns
$t_{a(OE)}$	\overline{OE} to output delay	$\overline{CE} = V_{IL}$		60		60	ns
t_{DF}	\overline{OE} high to output float	$\overline{CE} = V_{IL}$	0	50	0	50	ns
t_{OH}	Output hold from \overline{CE} , \overline{OE} or address		0		0		ns

Note 3: V_{CC} must be applied simultaneously V_{PP} and removed simultaneously V_{PP} .

AC WAVEFORMS



Test conditions for A.C. characteristics

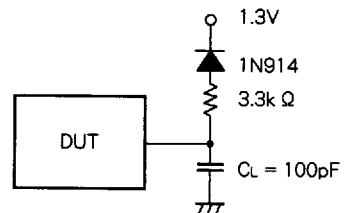
Input voltage: $V_{IL} = 0.45V$, $V_{IH} = 3.0V$

Input rise and fall times: $\leq 10\text{ns}$

Reference voltage at timing measurement: 1.5V

Output load: 1TTL gate + C_L (100pF)

or



CAPACITANCE

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
C_{IN}	Input capacitance (Address, \overline{CE} , \overline{OE} , PGM)	$T_a = 25^\circ\text{C}$, $f = 1\text{MHz}$, $V_i = V_o = 0V$			15	pF
C_{OUT}	Output capacitance				15	pF

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PROGRAM OPERATION

WORD PROGRAMMING ALGORITHM

First set $V_{CC} = 6V$, $V_{PP} = 12.5V$ and then set an address to first address to be programmed. After applying 0.2ms program pulse (PGM) to the address, verify is performed. If the output data of that address is not verified correctly, apply one more 0.2ms program pulse. The programmer continues 0.2ms pulse-then-verify routines until the device verify correctly or twenty five of these pulse-then-verify routines have been completed. The programmer also maintains its total

number of 0.2ms pulse applied to that address in register X. And then applied a program pulse X times of 0.2ms width as an overprogram pulse. When the programming procedure above is finished, step to the next address and repeat this procedure till last address to be programmed. When the entire addresses have been programmed completely, all addresses should be verified with $V_{CC} = V_{PP} = 5V$.

DC ELECTRICAL CHARACTERISTICS ($T_a = 25 \pm 5^\circ C$, $V_{CC} = 6V \pm 0.25V$, $V_{PP} = 12.5V \pm 0.3V$, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
I_{LI}	Input leakage current	$V_{IN} = 0 \sim V_{CC}$			10	μA
V_{OL}	Output low voltage (verify)	$I_{OL} = 2.1mA$			0.45	V
V_{OH}	Output high voltage (verify)	$I_{OH} = -400 \mu A$	2.4			V
V_{IL}	Input low voltage		-0.1		0.8	V
V_{IH}	Input high voltage		2.2		V_{CC}	V
I_{CC}	V_{CC} supply current				30	mA
I_{PP}	V_{PP} supply current	$PGM = V_{IL}$			50	mA

AC ELECTRICAL CHARACTERISTICS ($T_a = 25 \pm 5^\circ C$, $V_{CC} = 6V \pm 0.25V$, $V_{PP} = 12.5V \pm 0.3V$, unless otherwise noted)

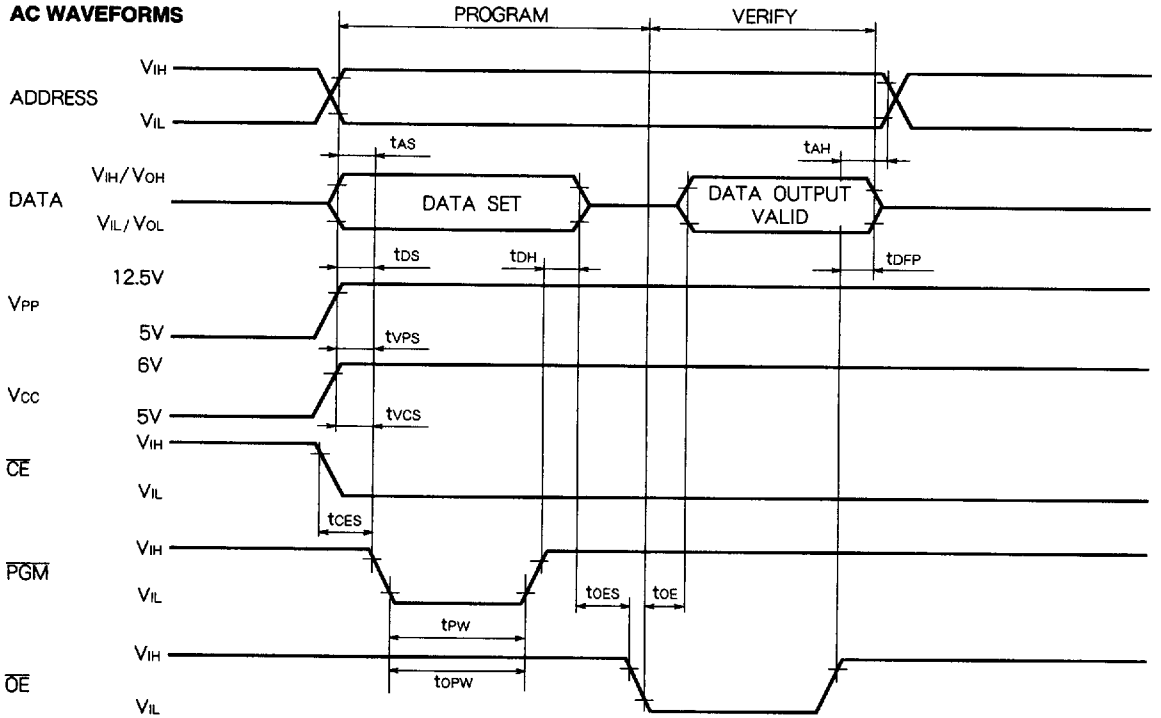
Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
t_{AS}	Address setup time		2			μs
t_{OES}	\overline{OE} setup time		2			μs
t_{DS}	Data setup time		2			μs
t_{AH}	Address hold time		0			μs
t_{DH}	Data hold time		2			μs
t_{DFP}	Chip enable to output float delay		0		130	ns
t_{VCS}	V_{CC} setup time		2			μs
t_{VPS}	V_{PP} setup time		2			μs
t_{PW}	PGM initial program pulse width		0.19	0.2	0.21	ms
t_{OPW}	PGM over program pulse width		0.19		5.25	ms
t_{CES}	\overline{CE} setup time		2			μs
t_{OE}	Data valid from \overline{OE}				150	ns

Note 4: V_{CC} must be applied simultaneously V_{PP} and removed simultaneously V_{PP} .

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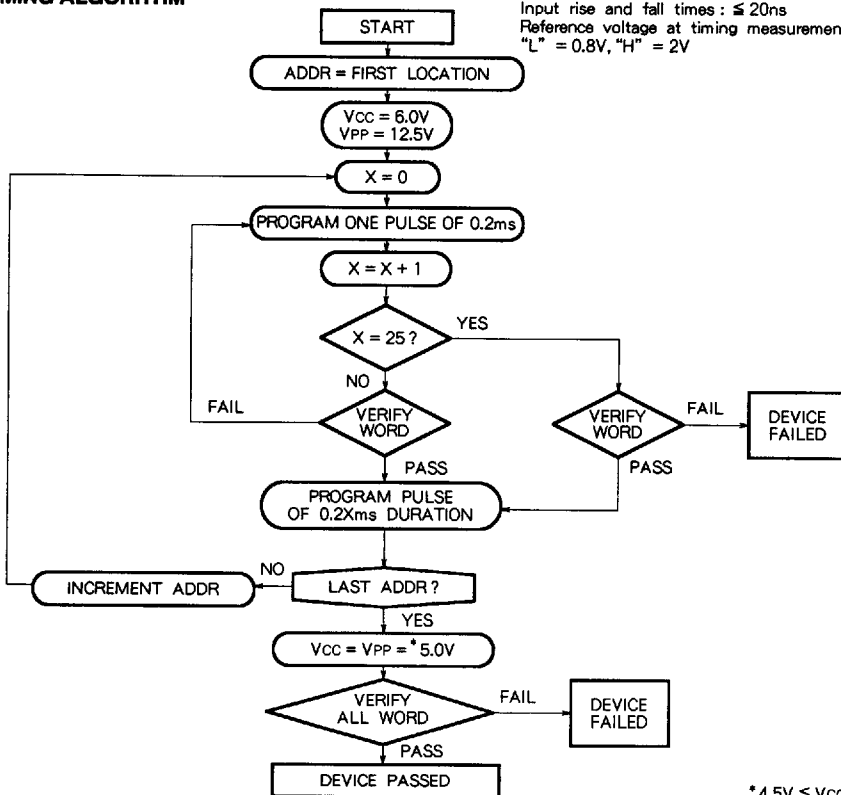
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AC WAVEFORMS



Test conditions for A.C. characteristics
Input voltage : $V_{IL} = 0.45V, V_{IH} = 2.4V$
Input rise and fall times : $\leq 20ns$
Reference voltage at timing measurement : Input, Output
"L" = 0.8V, "H" = 2V

WORD PROGRAMMING ALGORITHM
FLOW CHART



*4.5V \leq VCC = VPP \leq 5.5V

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PAGE PROGRAMMING ALGORITHM

First set $V_{CC} = 6V$, $V_{PP} = 12.5V$ and then set an address to first page address to be programmed. After data of 2 words are latched, these latch data are programmed simultaneously by applying 0.2ms program pulse. Then a verify is performed. If each output data is not verified correctly, apply one more 0.2ms program pulse. The programmer continues 0.2ms pulse-then-verify routines until each output data is verified correctly or twenty five of these pulse-then-verify routines have been completed. The programmer also maintains its total number

of 0.2ms pulse applied to that page addresses in register X. And then applied a program pulse X times of 0.2ms width as an overprogram pulse. When the programming procedure above is finished, step to the next page address and repeat this procedure till last page address to be programmed. When the entire page addresses have been programmed completely, all addresses should be verified with $V_{CC} = V_{PP} = 5V$.

DC ELECTRICAL CHARACTERISTICS ($T_a = 25 \pm 5^\circ C$, $V_{CC} = 6V \pm 0.25V$, $V_{PP} = 12.5V \pm 0.3V$, unless otherwise noted)

Symbol	Parameter	Test condition	Limits			Unit
			Min	Typ	Max	
I _{LI}	Input leakage current	$V_{IN} = 0 \sim V_{CC}$			10	μA
V _{OL}	Output low voltage (verify)	$I_{OL} = 2.1mA$			0.45	V
V _{OH}	Output high voltage (verify)	$I_{OH} = -400 \mu A$				V
V _{IL}	Input low voltage		-0.1		0.8	V
V _{IH}	Input high voltage		2.2		V_{CC}	V
I _{CC}	V_{CC} supply current				30	mA
I _{PP}	V_{PP} supply current	$PGM = V_{IL}$			100	mA

AC ELECTRICAL CHARACTERISTICS ($T_a = 25 \pm 5^\circ C$, $V_{CC} = 6V \pm 0.25V$, $V_{PP} = 12.5V \pm 0.3V$, unless otherwise noted)

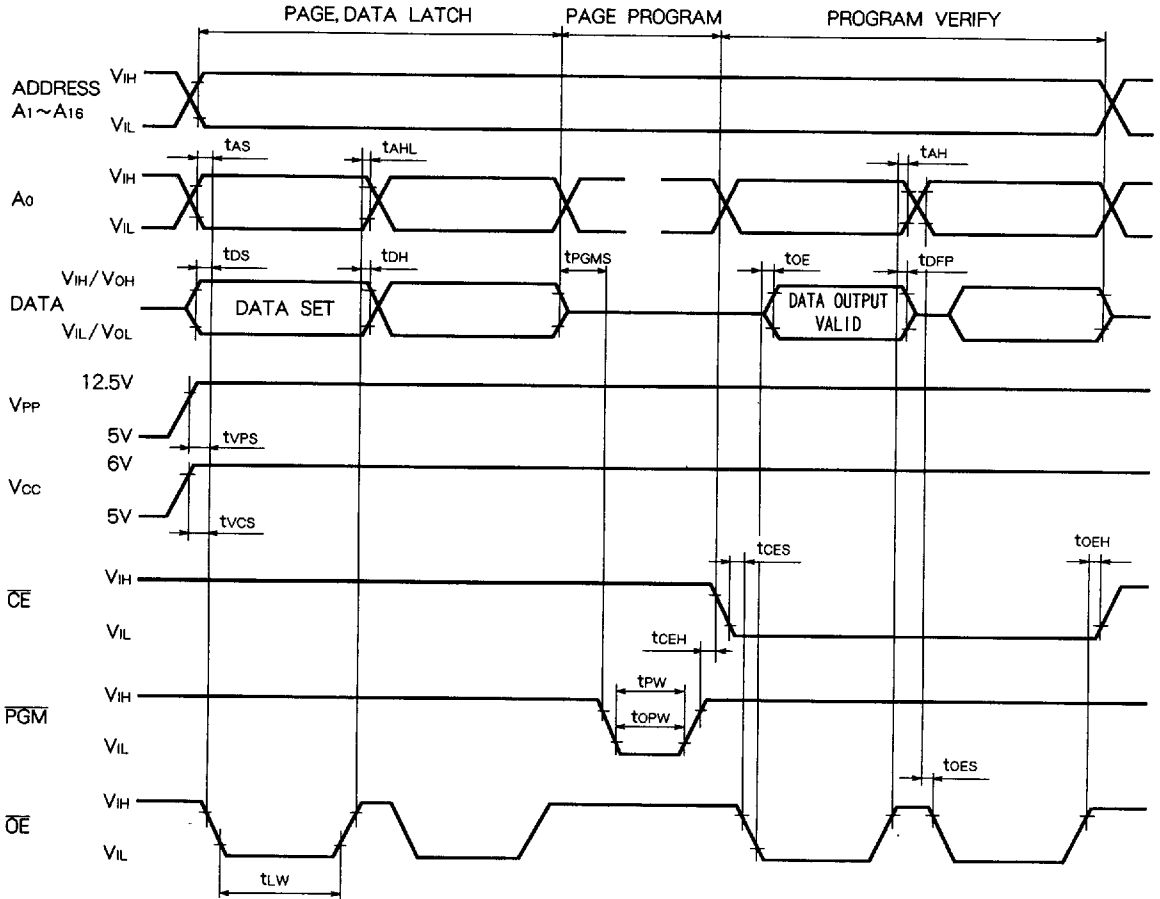
Symbol	Parameter	Test condition	Limits			Unit
			Min	Typ	Max	
t _{AS}	Address setup time		2			μs
t _{oES}	\overline{OE} setup time		2			μs
t _{DS}	Data setup time		2			μs
t _{AH}	Address hold time		0			μs
t _{AHL}			2			μs
t _{DH}	Data hold time		2			μs
t _{DFF}	\overline{OE} to output float delay		0		130	ns
t _{VCS}	V_{CC} setup time		2			μs
t _{VPS}	V_{PP} setup time		2			μs
t _{PW}	PGM initial program pulse width		0.19	0.2	0.21	ms
t _{OPW}	PGM over program pulse width		0.19		5.25	ms
t _{CES}	\overline{CE} setup time		2			μs
t _{oE}	Data valid from \overline{OE}				150	ns
t _{LW}	Data latch time		1			μs
t _{PGMS}	PGM setup time		2			μs
t _{CEH}	\overline{CE} hold time		2			μs
t _{oEH}	\overline{OE} hold time		2			μs

Note 5: V_{CC} must be applied simultaneously V_{PP} and removed simultaneously V_{PP} .

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AC WAVEFORMS



Test condition for A.C. characteristics

Input voltage : $V_{IL} = 0.45V, V_{IH} = 2.4V$

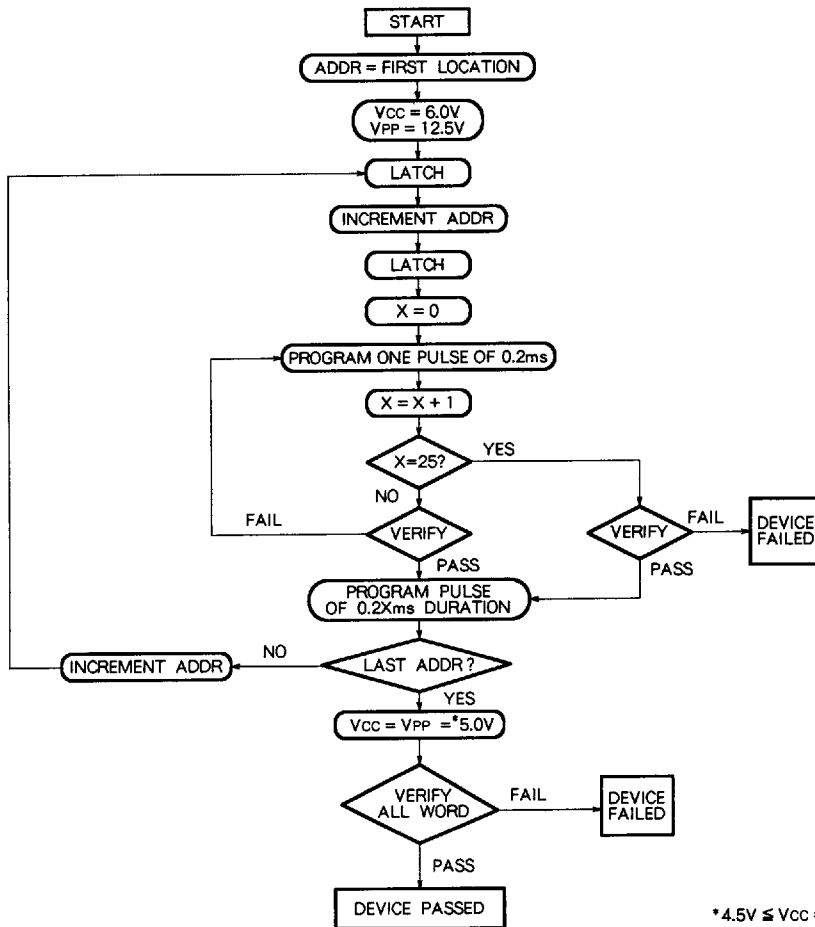
Input rise and fall time : (10%~90%) : $\leq 20ns$

Reference voltage timing measurement : Input, Output "L" = 0.8V, "H" = 2V

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PAGE PROGRAMMING ALGORITHM
FLOW CHART



*4.5V ≤ VCC = VPP ≤ 5.5V

DEVICE IDENTIFIER MODE

The Device Identifier Mode allows the reading of a binary code from the EPROM that identifies the manufacturer and device type.

The EPROM Programmer reads the manufacturer code and the device code and automatically selects the corresponding programming algorithm.

M5M27C202K,JK-12I,-15I DEVICE IDENTIFIER CODE

Code	Pin	A0 (21)	D15 (3)	D14 (4)	D13 (5)	D12 (6)	D11 (7)	D10 (8)	D9 (9)	D8 (10)	D7 (12)	D6 (13)	D5 (14)	D4 (15)	D3 (16)	D2 (17)	D1 (18)	D0 (19)	Hex Data
Manufacturer code	V _{IL}	0	0	0	0	0	0	0	0	0	0	0	0	1	1	1	0	0	001C
Device code	V _{IH}	0	0	0	0	0	0	0	0	0	0	0	0	0	1	0	1	1	000B

Note 6 : A9 = 12.0 ± 0.5V.

A1~A8, A10~A16, CE, OE = V_{IL}, PGM = V_{IH}.

VCC = VPP = 5V ± 10%.